## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | SABHARWAL ET AL. | Examiner | Art Unit | Dang T. Nguyen | 2824 | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,515,893 B1	02-2003	Bhavnagarwala, Azeez J.	365/154
	В	US-2003/0081492 A1	05-2003	Farrell et al.	365/238.5
	С	US-6,920,060 B2	07-2005	Chow et al.	365/145
	D	US-2005/0128789 A1	06-2005	Houston, Theodore W.	365/154
	Ε	US-2003/0012048 A1	01-2003	Chappell et al.	365/154
	F	US-			
	G	US-			
	Η	US-			
	1	US-			
	J	US-			·
	К	US-			
	٦	US-			
	Μ	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Ρ		,	٠		
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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